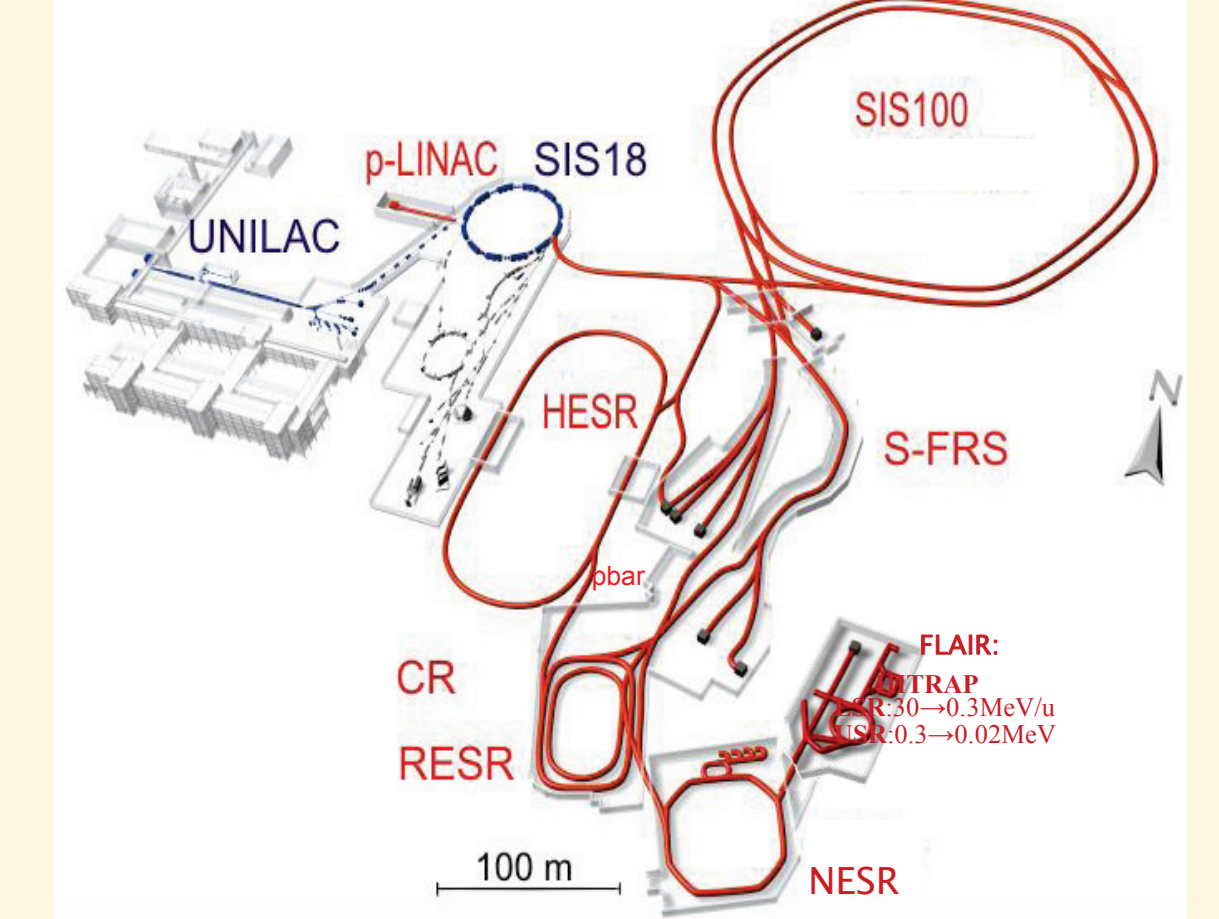
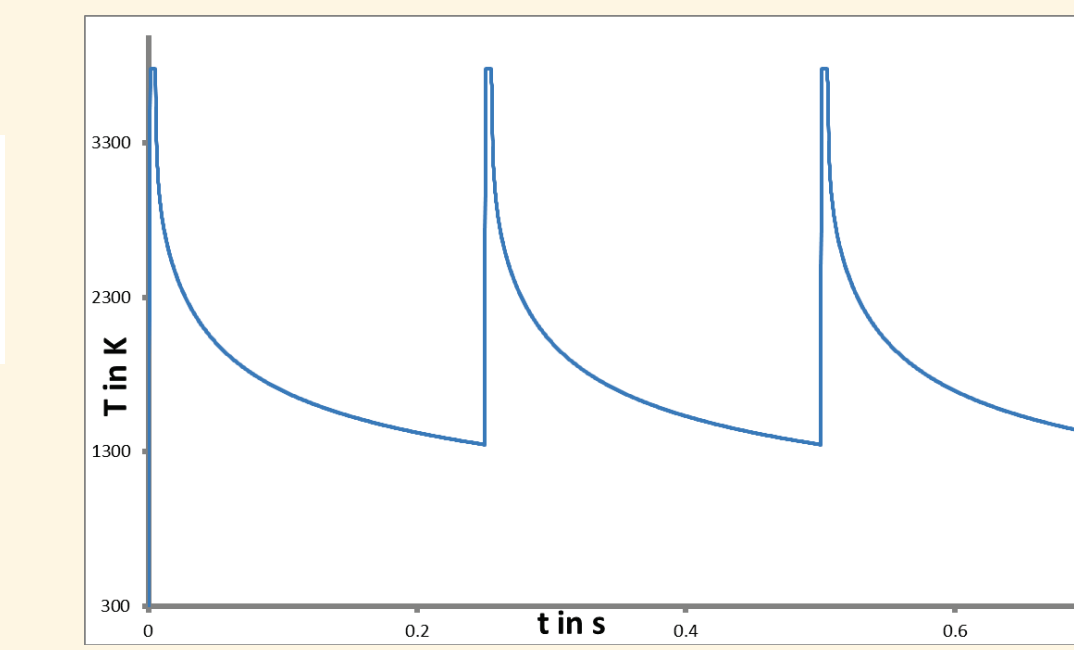
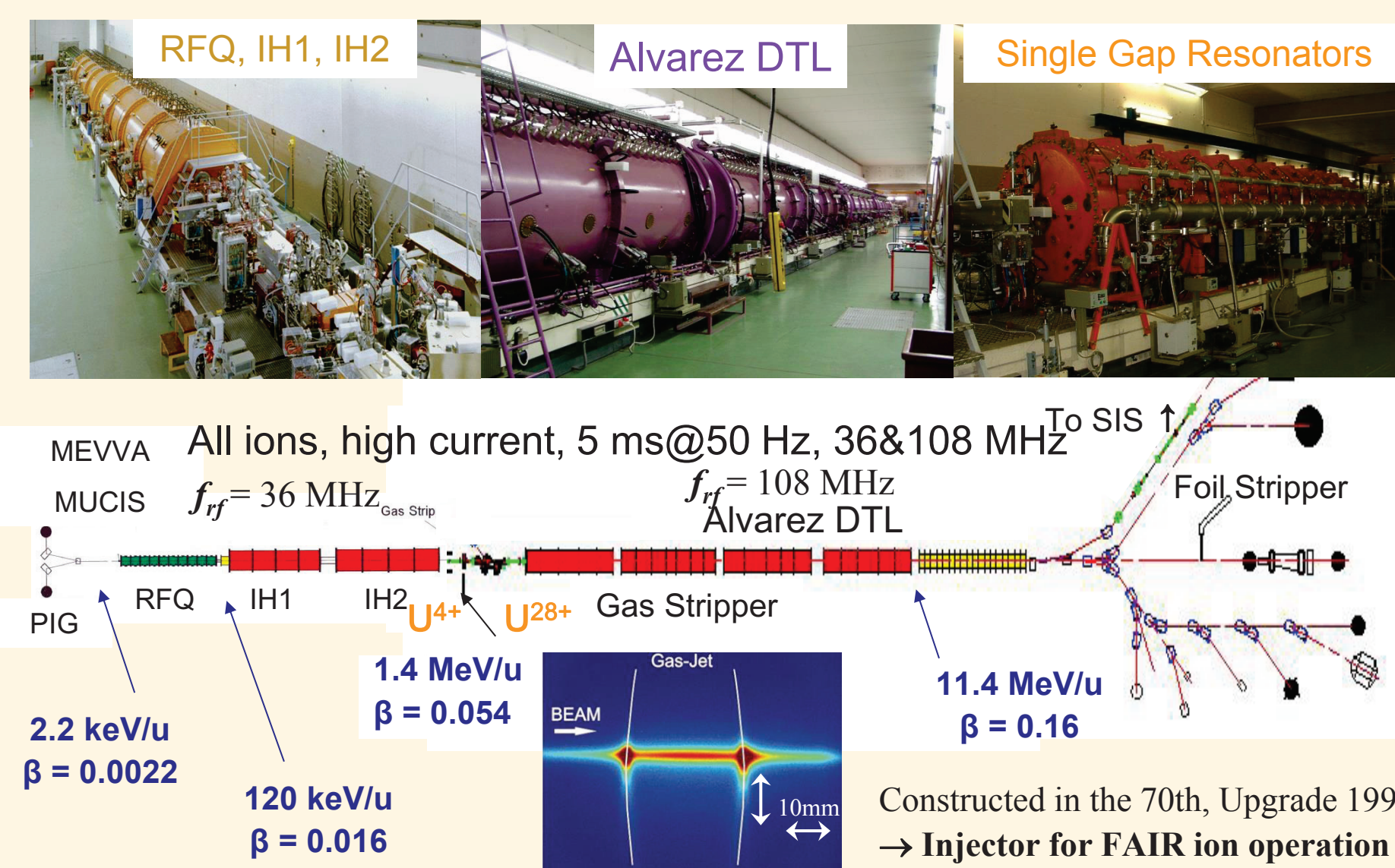


Abstract

At the heavy ion LINAC at GSI, a non-invasive Bunch Shape Monitor has been tested with several different ion beams at 11.4 MeV/u. The monitors principle is based on the analysis of secondary electrons liberated from the residual gas by the beam impact. These electrons are accelerated, filtered by an electrostatic energy analyzer and deflected by an rf-deflector, acting as a time-to-space converter. A MCP-phosphor combination acts as a detector. For the applied beam settings this Bunch Shape Monitor is able to obtain longitudinal profiles down to a RMS of 300 ps with a RMS resolution of 25 ps, corresponding to 0.5° @ 36 MHz. The applicability is demonstrated.

The GSI UNILAC Facility

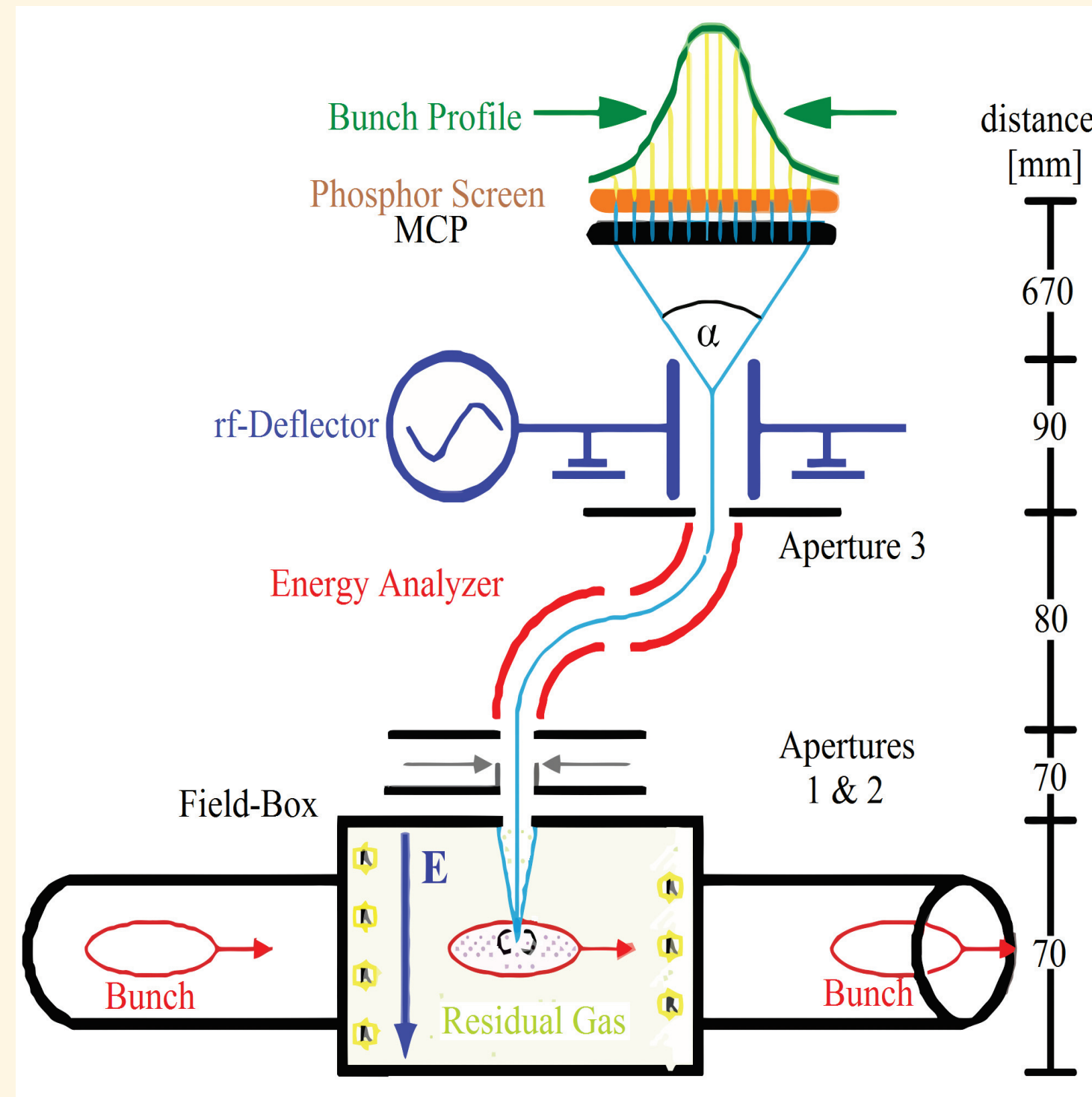


FAIR physics:

- Rare isotopes beams
- Atomic & mat. physics
- Hadron spectroscopy with anti-protons dedicated proton LINAC

Typically ion current from 0.1 to 1 mA, depending on isotope.

Scheme of the non-intersecting Bunch Shape Monitor



Scheme for non-destructive device:

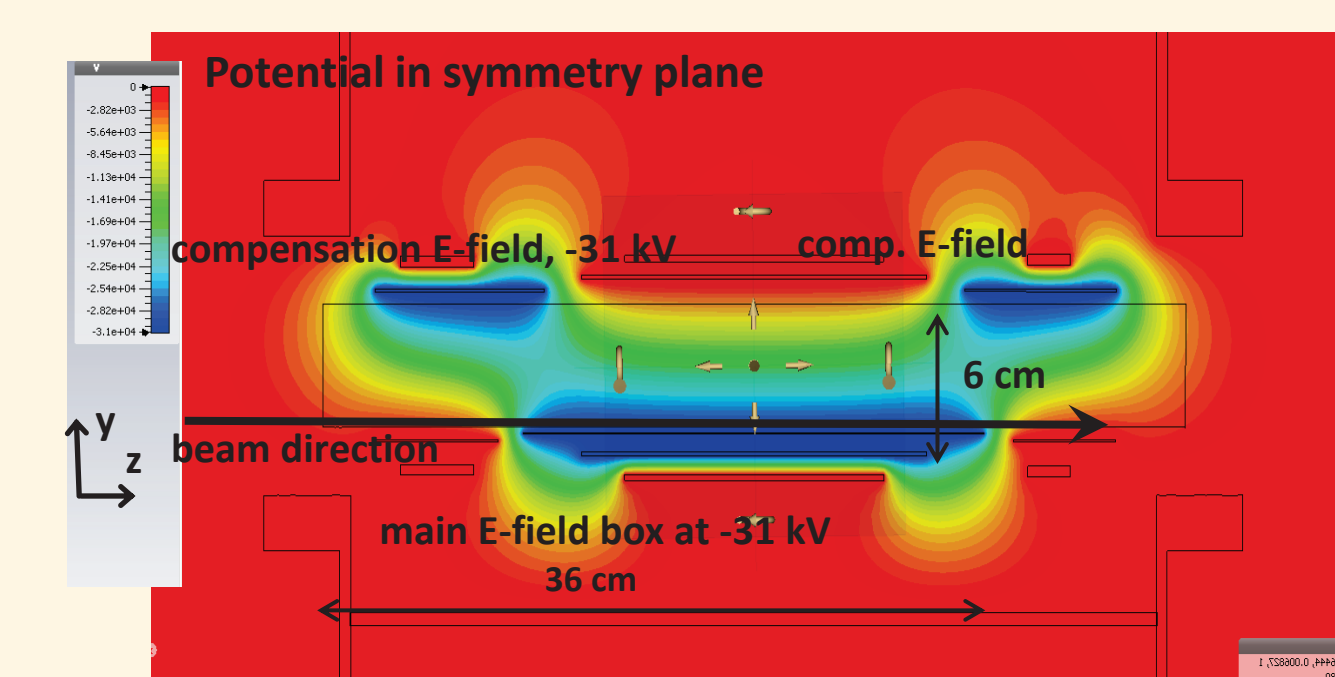
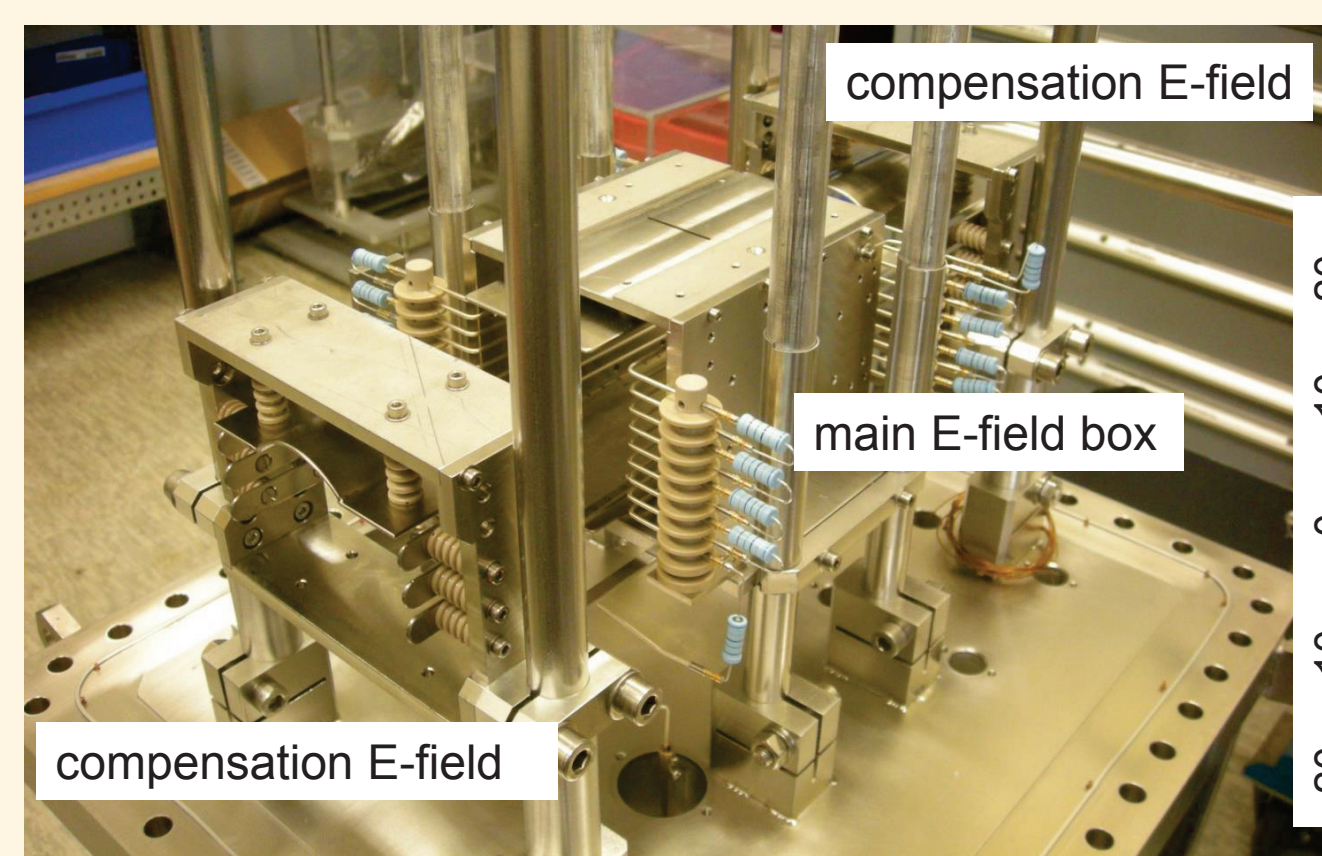
- Secondary electrons from residual gas
- Acceleration by electric field (like for Ionization Profile Monitor)
- Target localization by apertures and electro-static analyzer ($\Delta y = 0.2$ to 2 mm, $\Delta z = 0.2$ to 1 mm)
- rf-resonator as 'time-to-space' converter $\lambda/4$ resonator, $Q_0 \approx 300$, $P_{\text{in}} = 50 \text{ W}$ max.
- Readout by MCP + Phosphor + CCD
- Measurement within several macro-pulses

Field-Box Design

Compensation of beam deflection:

- E-field for box: 30 kV/ 70mm = 4.2 kV/mm
- Short intersection length with reversed field
- compact design realized

⇒ Beam based tests proved functionality



➤ Angle of deflection for protons $\alpha \approx 400 \mu\text{rad}$

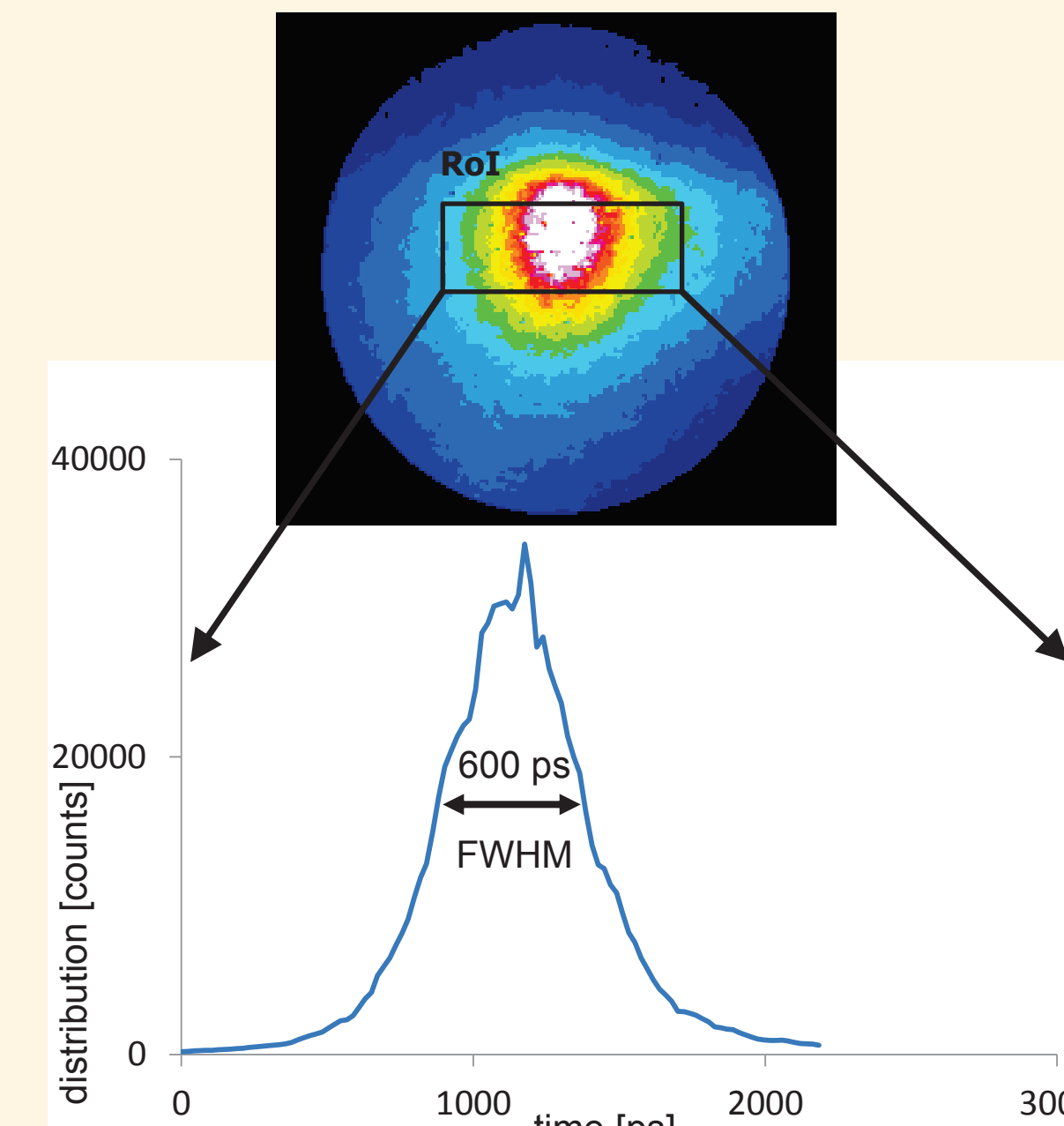
Compensation f based on CST code:

$$f = \frac{\int E_y(\text{compensate}) \cdot dz}{\int E_y(\text{un-compensate}) \cdot dz}$$

- 4 μrad left within $\varnothing 20 \text{ mm}$
- 48 μrad left within $\varnothing 50 \text{ mm}$

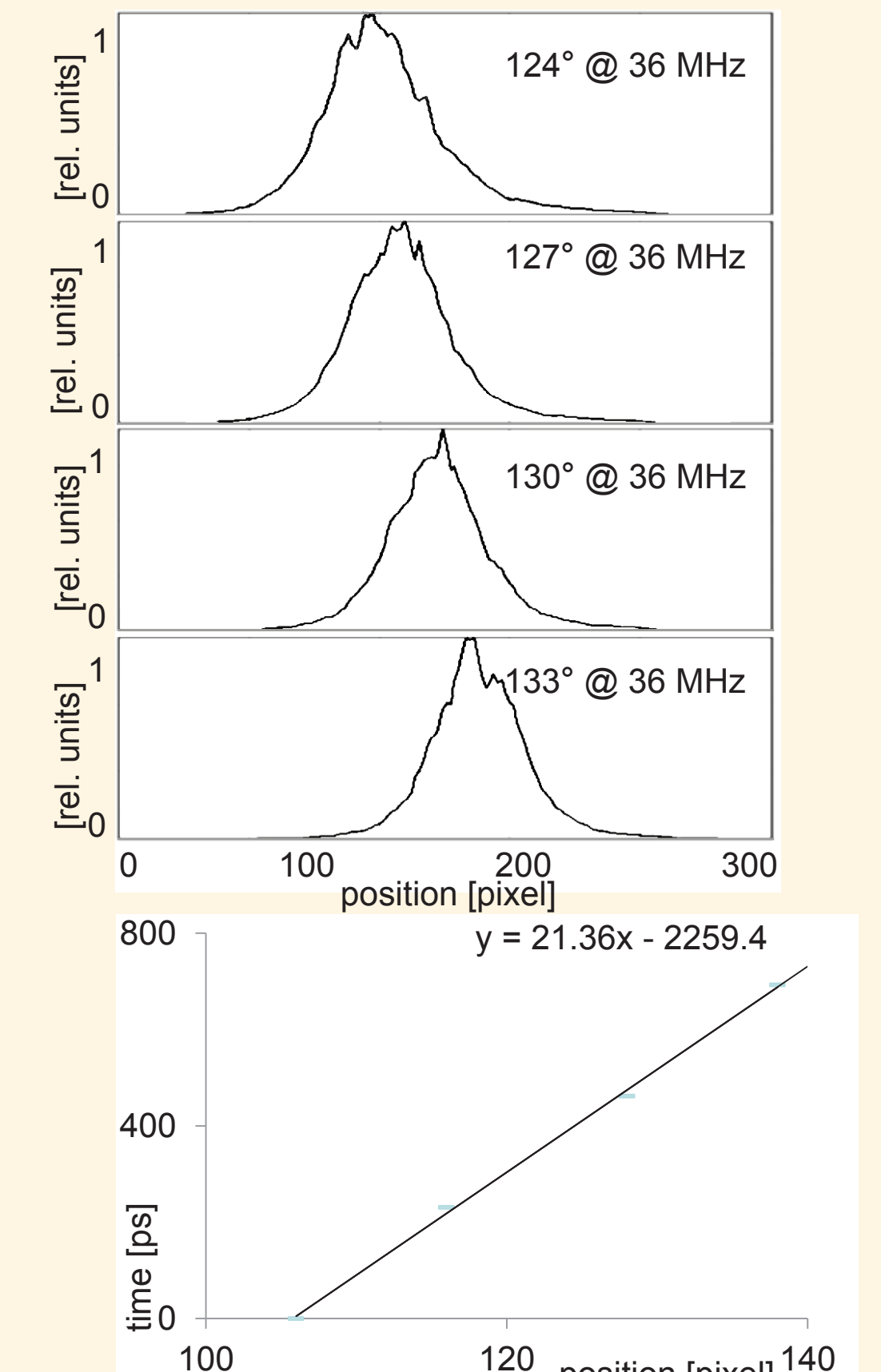
Typical Results and their Discussion

Profile Measurement:



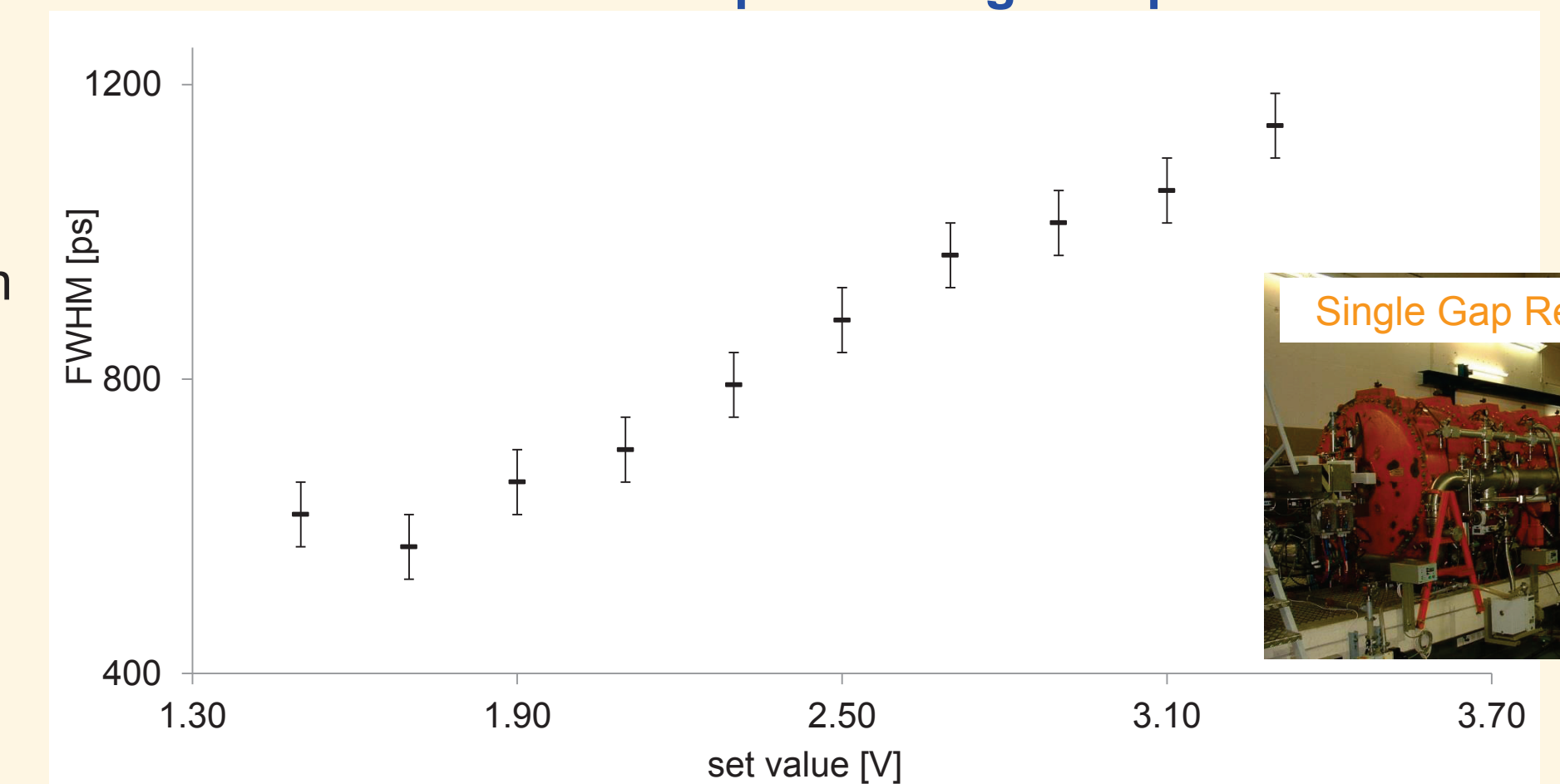
- Ni^{28+} , $I = 900 \mu\text{A}$, $t_p = 180 \mu\text{s}$, $P = 5 \cdot 10^{-6} \text{ mbar}$, 16 averages,
- RMS 290 ps ⇒ FWHM 681 ps
- FWHM read-off = 600 ps
- Phase calibration: 21 ps/px

Phase Calibration:



Demonstration of Usability

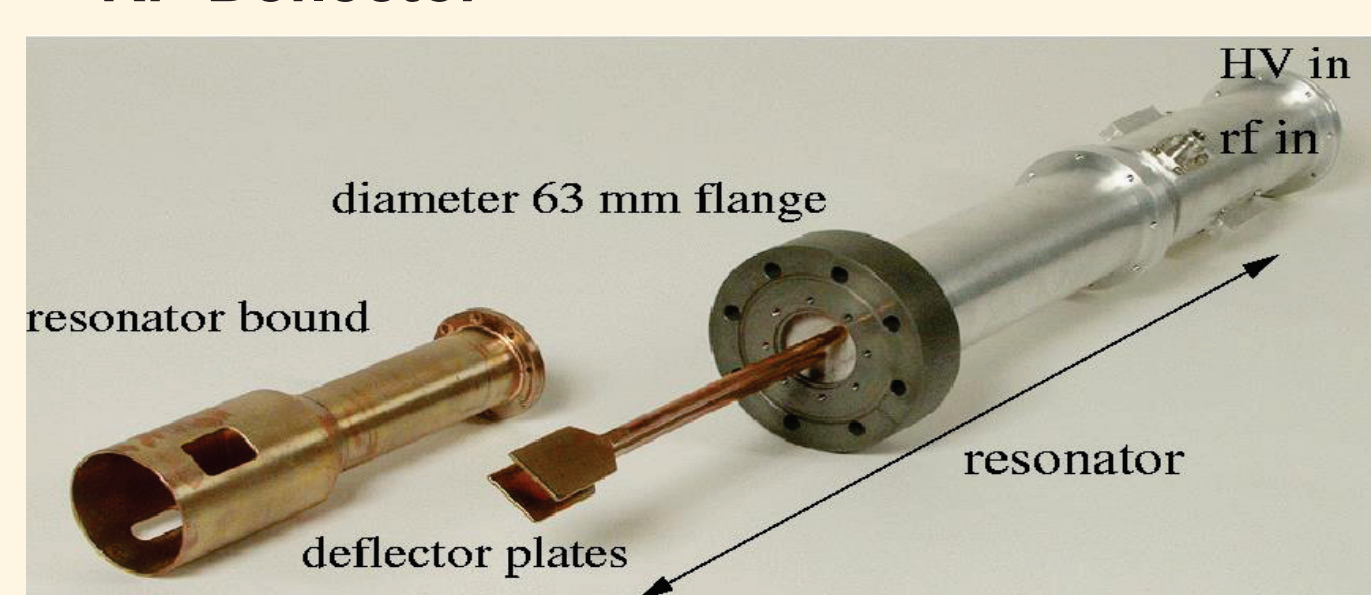
Bunch Profile Sweep with Single Gap Resonator



- N^{7+} , $I = 5 \text{ mA}$, $t_p = 220 \mu\text{s}$, $P = 1 \cdot 10^{-5} \text{ mbar}$
- Phase calibration: 195 ps/mm
- FWHM 570 ps -1150 ps
- 64 averages per Profile
- Focus passes through BSM

⇒ BSM is sensitive for Bunch Profile sweep

RF-Deflector



The rf-deflector produced by INR Troitzk:

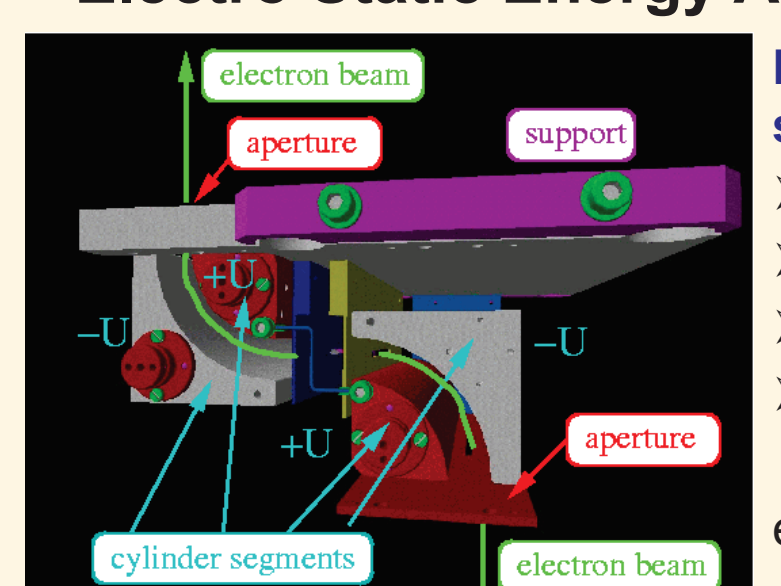
Parallel wire $\lambda/4$ -resonator:

	36 MHz	108 MHz
l_0	800 mm	800 mm
length	800 mm	800 mm
P_{max}	100 W	30 W
Q_0	290	370
t_{max}	6 ms	6 ms
a_{max}	3°	3°

Additional action:

- Common U_z up to 7 kV acting as einzel lens
- Different U_d up to 1 kV acting as steerer

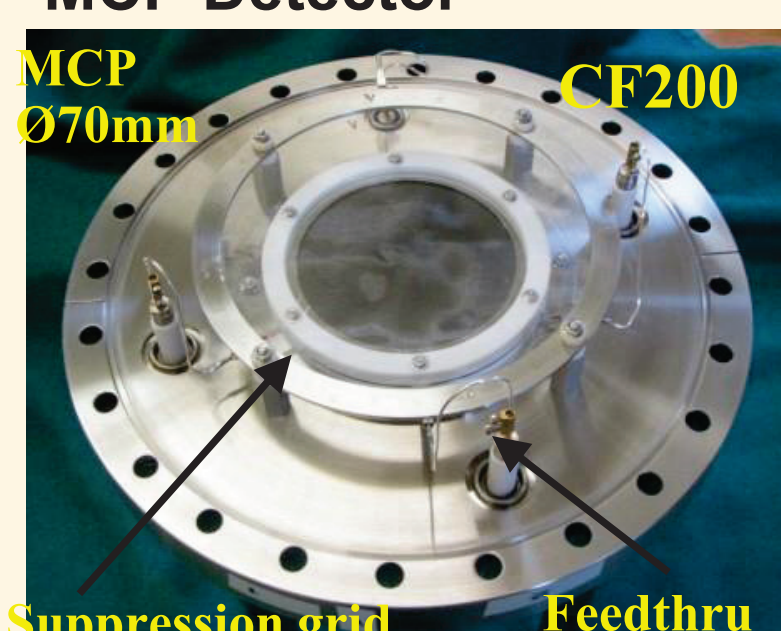
Electro Static Energy Analyzer



Energy analyzer for source volume restriction:

- Radius $\rho = 30 \text{ mm}$,
- 90° bending, $\pm 5.5 \text{ kV}$
- Point-to-point focusing
- Remote controlled aperture: 0.1 to 2 mm
- e.g. for $\pm 0.25 \text{ mm}$ & $\pm 0.5 \text{ mm}$ ⇒ $\pm 0.2 \text{ mm}$ vert. prolongation (comparable to wire)

MCP Detector



- MCP-phosphor module: Drift from rf-deflector: 670 mm corresp. to $\alpha_{\text{max}} = 3^\circ$
- MCP: Hamamatsu $\varnothing 77 \text{ mm}$
- Phosphor: P20
- CCD: PCO SensiCam VGA 12 bit, cooled to -10° C digital interface

MCP Detector Background

Pressure induced Background:

- N^{7+} , $I = 900 \mu\text{A}$, $t_p = 180 \mu\text{s}$
- 20.5 keV, 1600 V MCP,
- 16 averages
- Apertures are closed
- Plot shows linear behaviour

⇒ Background strongly depending on the pressure

Field Box induced Background:

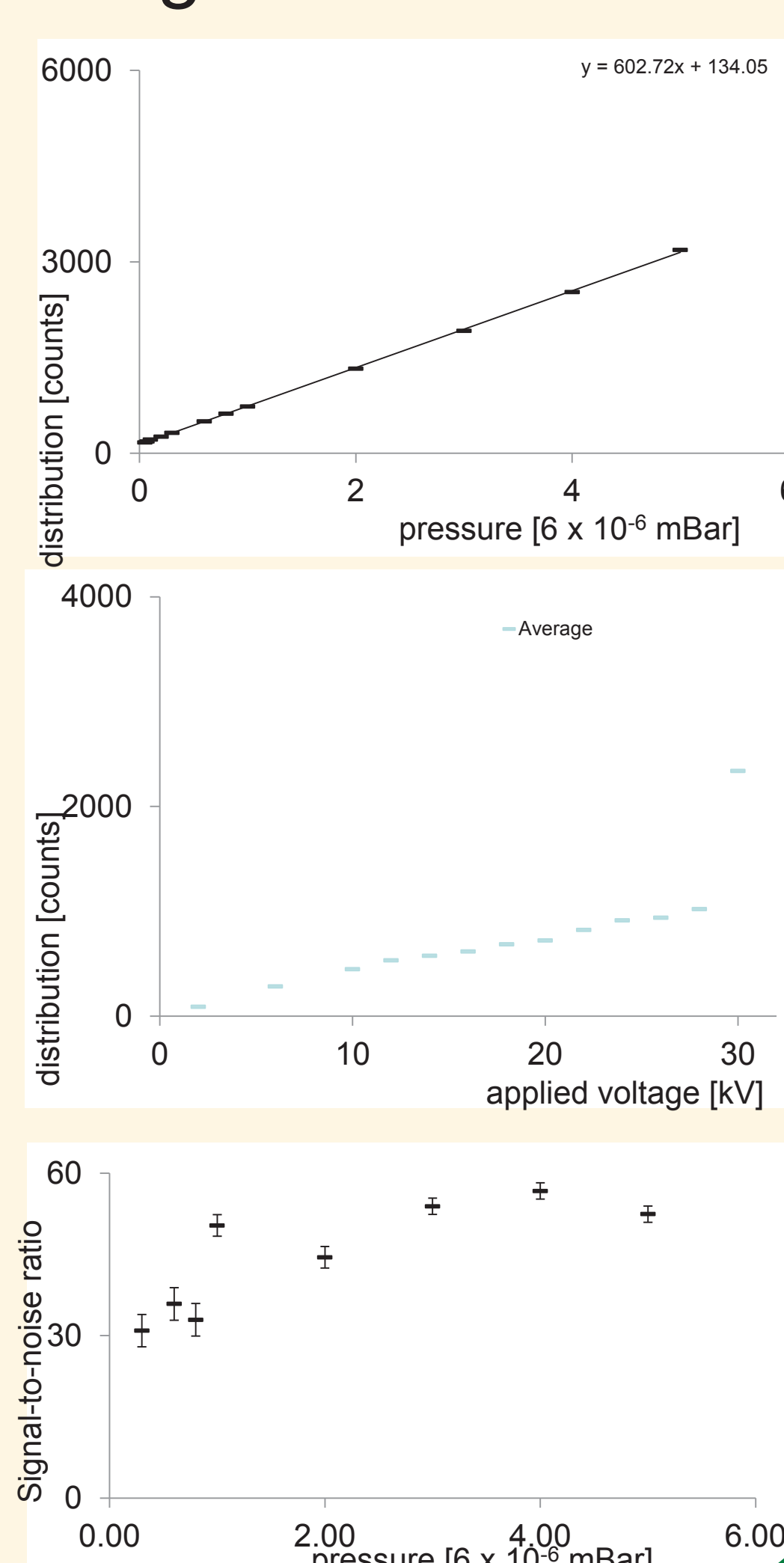
- N^{7+} , $I = 900 \mu\text{A}$, $t_p = 180 \mu\text{s}$
- $1 \times 10^{-6} \text{ mBar}$, 1600 V MCP
- 8 averages
- Apertures are closed
- At 30 kV a threshold occurs

⇒ X-rays responsible for background

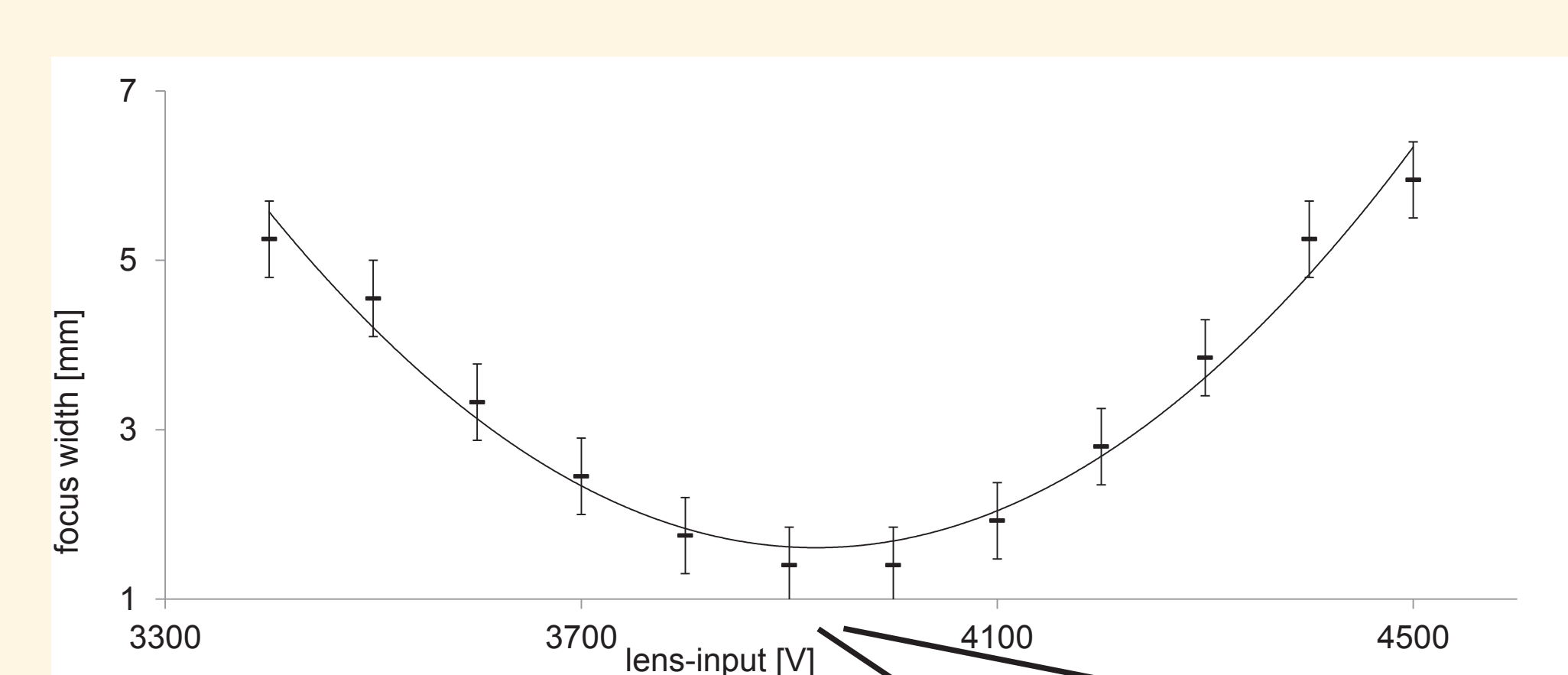
Signal-to-noise ratio:

- N^{7+} , $I = 900 \mu\text{A}$, $t_p = 180 \mu\text{s}$
- 1800 V MCP, 8 averages
- SNR gets better with higher pressure

⇒ Signal-to-noise ratio sufficient for profile measurements



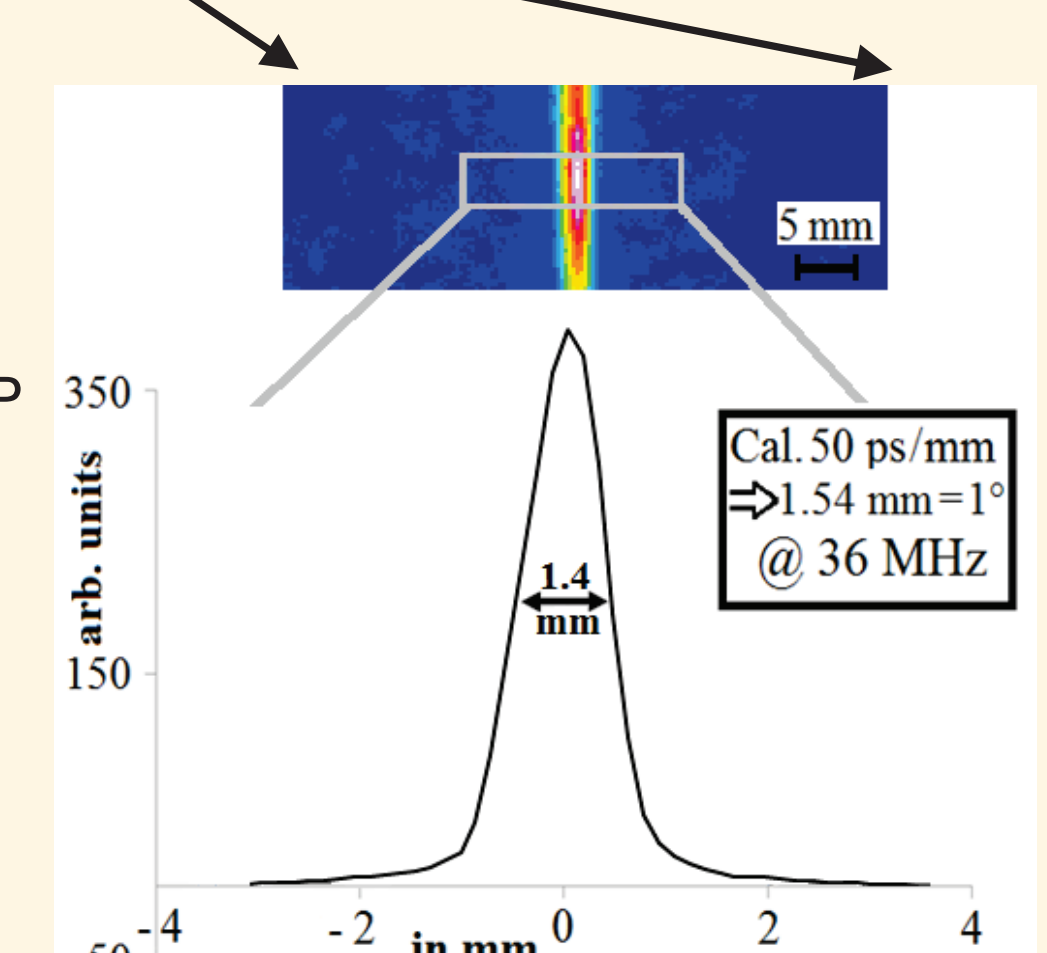
Focus Width determines Resolution



Aperture Adjustment

- N^{7+} , $I = 900 \mu\text{A}$, $t_p = 180 \mu\text{s}$
- Apertures set to 0.5 mm open
- 11.5 keV, $7 \times 10^{-7} \text{ mBar}$, 1500 V MCP
- Optimum easy achievable
- Up to 0.1 mm setting possible but intensity will go to zero

⇒ RMS 0.6 mm focus leads to 25 ps total resolution



Summary and Outlook

- Monitor design: adaption of 'Feschenko Monitor' to non-invasive device
- Realization and successful beam-based test has been executed
- Determination of resolution → sufficient for application, monitor can be used at UNILAC
- Resolution can be matched to bunch length by rf power adaption
- Background is significantly decreased, present background, if the ion beam is well aligned, is due to x-ray radiation